

January 2015

FJBE2150D

ESBC[™] Rated NPN Silicon Transistor

ESBC Features (FDC655 MOSFET)

V _{CS(ON)}	I _C	Equiv. R _{CS(ON)}
0.131 V	0.5 A	$0.261~\Omega^{(1)}$

- · Low Equivalent On Resistance
- · Very Fast Switch: 150 kHz
- Squared RBSOA: Up to 1500 V
- · Avalanche Rated
- Low Driving Capacitance, No Miller Capacitance (Typ. 12 pF Capacitance at 200 V)
- · Low Switching Losses
- Reliable HV Switch: No False Triggering due to High dv/dt Transients

Applications

- · High-Voltage and High-Speed Power Switches
- Emitter-Switched Bipolar/MOSFET Cascode (ESBC[™])
- Smart Meters, Smart Breakers, HV Industrial Power Supplies
- · Motor Drivers and Ignition Drivers

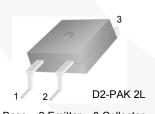
Description

The FJBE2150D is a low-cost, high-performance power switch designed to be used in an ESBC[™] configuration in applications such as: power supplies, motor drivers, smart grid, or ignition switches. The power switch is designed to operate up to 1500 volts and up to 3 amps, while providing exceptionally low on-resistance and very low switching losses.

The ESBC[™] switch is designed to be driven using off-the-shelf power supply controllers or drivers. The ESBC[™] MOSFET is a low-voltage, low-cost, surface-mount device that combines low-input capacitance and fast switching. The ESBC[™] configuration further minimizes the required driving power because it does not have Miller capacitance.

The FJBE2150D provides exceptional reliability and a large operating range due to its square Reverse-Bias-Safe-Operating-Area (RBSOA) and rugged design. The device is avalanche rated and has no parasitic transistors, so is not prone to static dv/dt failures.

The power switch is manufactured using a dedicated high-voltage bipolar process and is packaged in high-voltage HV-D2PAK rated at 2500 V creepage and clearance.



1.Base 2.Emitter 3.Collector Figure 1. Pin Configuration

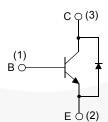


Figure 2. Internal Schematic Diagram

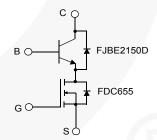


Figure 3. ESBC Configuration⁽²⁾

Ordering Information

Part Number Marking		Package	Packing Method	
FJBE2150DTU	J2150D	D2-PAK 2L (TO-263 2L)	Tube	

Notes:

- 1. Figure of Merit.
- 2. Other Fairchild MOSFETs can be used in this ESBC application.

Absolute Maximum Ratings

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only. Values are at $T_A = 25^{\circ}\text{C}$ unless otherwise noted.

Symbol	Parameter	Value	Unit	
V_{CBO}	Collector-Base Voltage	1500	V	
V _{CEO}	Collector-Emitter Voltage	800	V	
V _{EBO}	Emitter-Base Voltage	12	V	
I _C	Collector Current	2	Α	
I _{CP}	Collector Current (Pulse)	3	Α	
I _B	Base Current	1	Α	
I _{BP}	Base Current (Pulse)	2	Α	
P _D	Power Dissipation (T _C = 25°C)	110	W	
TJ	Operating and Junction Temperature Range	- 55 to +125	°C	
T _{STG}	Storage Temperature Range	- 65 to +150	°C	
EAS	Avalanche Energy (T _J = 25°C, 8 mH)	3.5	mJ	

Thermal Characteristics(3)

Values are at $T_A = 25$ °C unless otherwise noted.

Symbol	Parameter	Max.	Unit
$R_{ heta jc}$	Thermal Resistance, Junction to Case	1.13	°C/W
$R_{\theta ja}$	Thermal Resistance, Junction to Ambient	76.42	°C/W

Note:

3. Device mounted on FR-4 PCB, board size = 76.2 mm x 114.3 mm, land pattern 12.70 mm x 9.45 mm, trace size = 10 mil.

Electrical Characteristics(4)

Values are at $T_A = 25$ °C unless otherwise noted.

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{CBO}	Collector-Base Breakdown Voltage	$I_C = 0.5 \text{ mA}, I_E = 0$	1500	1689		V
BV _{CEO}	Collector-Emitter Breakdown Voltage	I _C = 5 mA, I _B = 0	800	870		V
BV _{EBO}	Emitter-Base Breakdown Voltage	$I_E = 0.5 \text{ mA}, I_C = 0$	12.0	14.8		V
I _{CES}	Collector Cut-off Current	$V_{CES} = 1500 \text{ V}, I_{E} = 0$		0.01	100	μΑ
I _{CEO}	Collector Cut-off Current	V _{CE} = 800 V, V _{BE} = 0		0.01	100	μΑ
I _{EBO}	Emitter Cut-off Current	V _{EB} = 12 V, I _C = 0		0.05	500	μΑ
h	DC Current Gain	$V_{CE} = 3 \text{ V}, I_{C} = 0.4 \text{ A}$	20	29	35	
h _{FE}	DC Current Gain	V _{CE} = 10 V, I _C = 5 mA	20	43		
		I _C = 0.25 A, I _B = 0.05 A		0.16		
V _{CE} (sat)	Collector-Emitter Saturation Voltage	I _C = 0.5 A, I _B = 0.167 A		0.12		V
		I _C = 1 A, I _B = 0.33 A		0.25		
\/ (oot)	Page Emitter Seturation Voltage	I _C = 500 mA, I _B = 50 mA		0.74	1.20	V
V _{BE} (sat)	Base-Emitter Saturation Voltage	I _C = 2 A, I _B = 0.4 A		0.85	1.20	V
C _{IB}	Input Capacitance	V _{EB} = 10 V, I _C = 0, f = 1 MHz		745	1000	pF
C _{OB}	Output Capacitance	V _{CB} = 200 V, I _E = 0, f = 1 MHz		15		pF
f _T	Current Gain Bandwidth Product	I _C = 0.1 A, V _{CE} = 10 V		5		MHz
V	Diodo Forward Voltago	I _F = 0.4 A		0.76	1.20	V
V _F	Diode Forward Voltage	I _F = 1 A		0.83	1.50	V

Note:

4. Pulse test: pulse width = 20 μs, duty cycle≤ 10%.

ESBC Configured Electrical Characteristics⁽⁵⁾

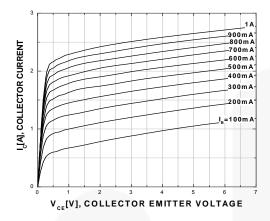
Values are at $T_A = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
f _T	Current Gain Bandwidth Product	I _C = 0.1 A,V _{CE} = 10 V		25		MHz
It _f	Inductive Current Fall Time			137		ns
t _s	Inductive Storage Time	$V_{GS} = 10 \text{ V}, R_G = 47 \Omega,$		350		ns
Vt _f	Inductive Voltage Fall Time	$V_{Clamp} = 500 \text{ V},$ $t_p = 3.1 \mu\text{s}, I_C = 0.3 \text{A},$		120		ns
Vt _r	Inductive Voltage Rise Time	I _B = 0.03 A, L _C = 1 mH, SRF = 480 kHz		100		ns
t _c	Inductive Crossover Time			137		ns
It _f	Inductive Current Fall Time			35		ns
t _s	Inductive Storage Time	$V_{GS} = 10 \text{ V}, R_G = 47 \Omega,$		980		ns
Vt _f	Inductive Voltage Fall Time	$V_{Clamp} = 500 \text{ V},$ $t_0 = 10 \mu\text{s}, I_C = 1 \text{A},$		30		ns
Vt _r	Inductive Voltage Rise Time	I _B = 0.2 A, L _C = 1 mH, SRF = 480 kHz		195		ns
t _c	Inductive Crossover Time			210		ns
V _{CSW}	Maximum Collector Source Voltage at Turn-off without Snubber	h _{FE} = 5, I _C = 2 A	1500			V
I _{GS(OS)}	Gate-Source Leakage Current	V _{GS} = ±20 V		1.0		nA
	Collector-Source On Voltage	$V_{GS} = 10 \text{ V}, I_C = 2 \text{ A}, I_B = 0.67 \text{ A}, h_{FE} = 3$	A, I _B = 0.67 A, h _{FE} = 3 2.210			V
		$V_{GS} = 10 \text{ V}, I_C = 1 \text{ A}, I_B = 0.33 \text{ A}, h_{FE} = 3$ $V_{GS} = 10 \text{ V}, I_C = 0.5 \text{ A}, I_B = 0.17 \text{ A}, h_{FE} = 3$ $V_{GS} = 10 \text{ V}, I_C = 0.3 \text{ A}, I_B = 0.06 \text{ A}, h_{FE} = 5$		0.321		
V _{CS(ON)}				0.131		
				0.166		
V _{GS(th)}	Gate Threshold Voltage	$V_{BS} = V_{GS}$, $I_{B} = 250 \mu\text{A}$		1.9		V
C _{iss}	Input Capacitance (V _{GS} = V _{CB} = 0)	V _{CS} = 25 V, f = 1 MHz		470		pF
Q _{GS(tot)}	Gate-Source Charge V _{CB} = 0	V _{GS} = 10 V, I _C = 8 A, V _{CS} = 25 V		9		nC
		V _{GS} = 10 V, I _D = 6.3 A		21		
r _{DS(ON)}	Static Drain-Source On Resistance	$V_{GS} = 4.5 \text{ V}, I_D = 5.5 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 6.3 \text{ A}, T_J = 125^{\circ}\text{C}$		26		mΩ
	OTT TOSISIATION			30		

Note:

5. Used typical FDC655 MOSFET values in table. Values can vary if other Fairchild MOSFETs are used.

Typical Performance Characteristics



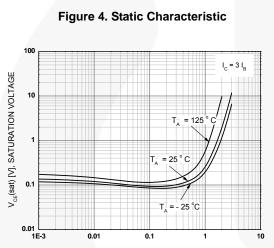


Figure 6. Collector-Emitter Saturation Voltage $h_{FE} = 3$

 $I_{\rm c}$ [A], COLLECTOR CURRENT

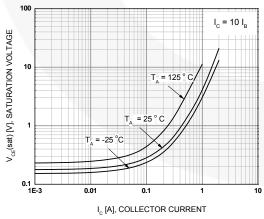


Figure 8. Collector-Emitter Saturation Voltage $h_{\text{FE}} = 10$

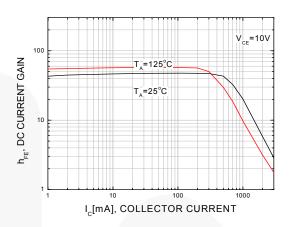


Figure 5. DC Current Gain

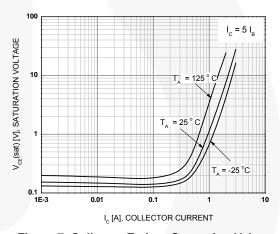


Figure 7. Collector-Emitter Saturation Voltage $h_{FE} = 5$

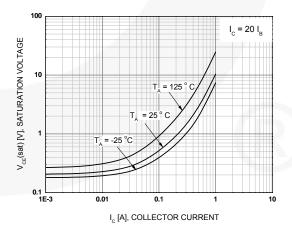


Figure 9. Collector-Emitter Saturation Voltage $h_{\text{FE}} = 20$

Typical Performance Characteristics (Continued)

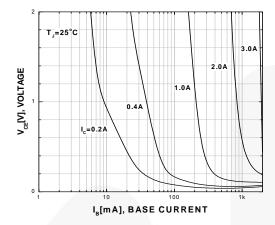


Figure 10. Typical Collector Saturation Voltage

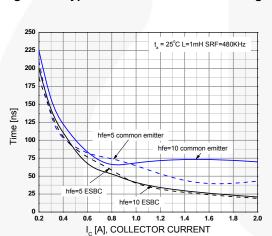


Figure 12. Inductive Load Collector Current Fall-Time (t_f)

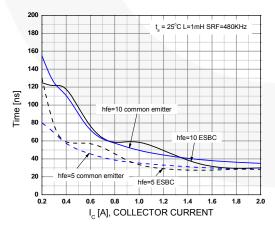


Figure 14. Inductive Load Collector Voltage Fall-Time (t_f)

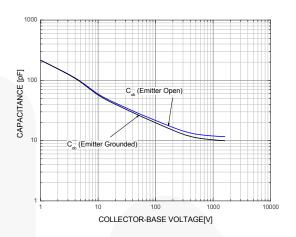


Figure 11. Capacitance

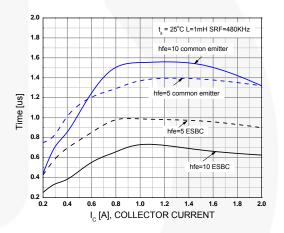


Figure 13. Inductive Load Collector Current Storage Time (t_{sto})

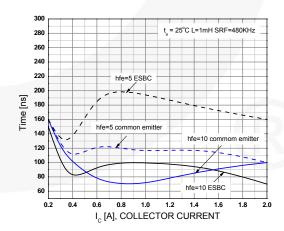
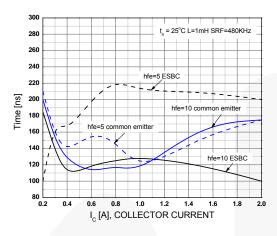


Figure 15. Inductive Load Collector Voltage Rise-Time (t_r)

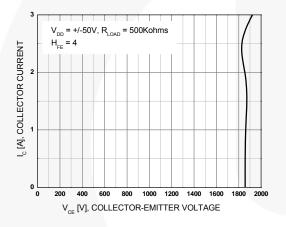
Typical Performance Characteristics (Continued)



3 V_{DD} = +/-50V, R_{LOAD} = 500KΩ V_{BE}(off) = 5V V_{BE}(off)

Figure 16. Inductive Load Collector Current / Voltage Crossover (t_c)

Figure 17. BJT Reverse Bias Safe Operating Area



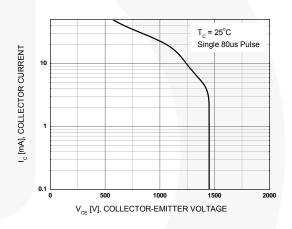


Figure 18. ESBC RBSOA

Figure 19. Crossover Forward Bias Safe Operating Area (FBSOA)

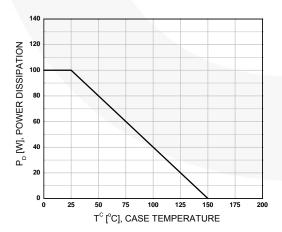


Figure 20. Power Derating

Test Circuits

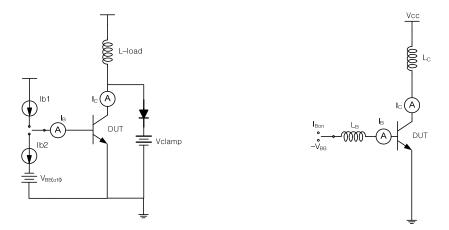


Figure 21. Test Circuit for Inductive Load and Reverse Bias Safe Operating

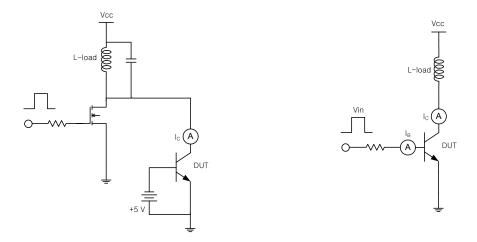


Figure 22. Energy Rating Test Circuit

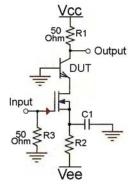


Figure 23. f_T Measurement

Figure 24. FBSOA

Test Circuits (Continued)

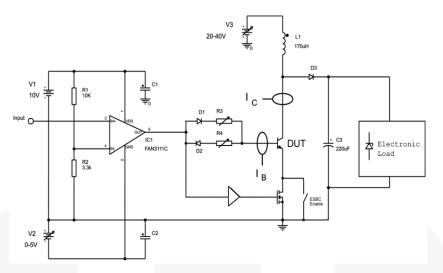


Figure 25. Simplified Saturated Switch Driver Circuit

Functional Test Waveforms

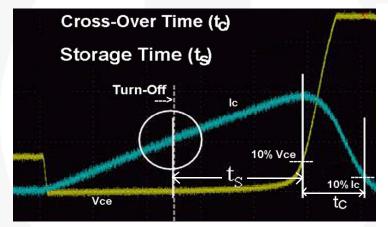


Figure 26. Crossover Time Measurement

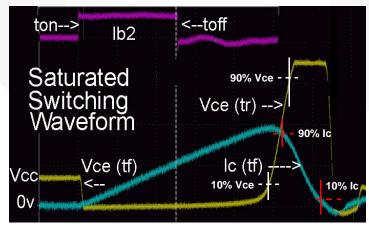


Figure 27. Saturated Switching Waveform

Functional Test Waveforms (Continued)

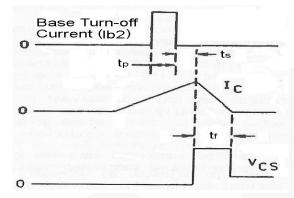


Figure 28. Storage Time - Common Emitter Base Turn-off (Ib2) to I_C Fall-Time

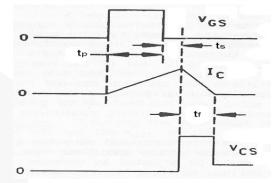
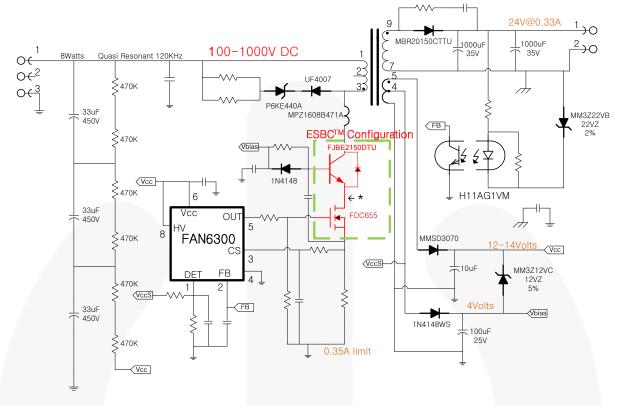


Figure 29. Storage Time - ESBC FET Gate (off) to I_C Fall-Time

Very Wide Input Voltage Range Supply



* Make short as possible

Figure 30. 8 W; Secondary-Side Regulation: 3 Capacitor Input; Quasi Resonant

Driving ESBC Switches

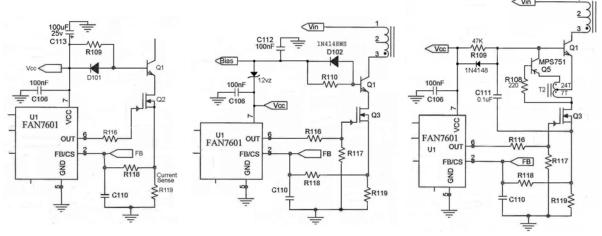


Figure 31. V_{CC} Derived

Figure 32. V_{bias} Supply Derived

Figure 33. Proportional Drive

Physical Dimensions

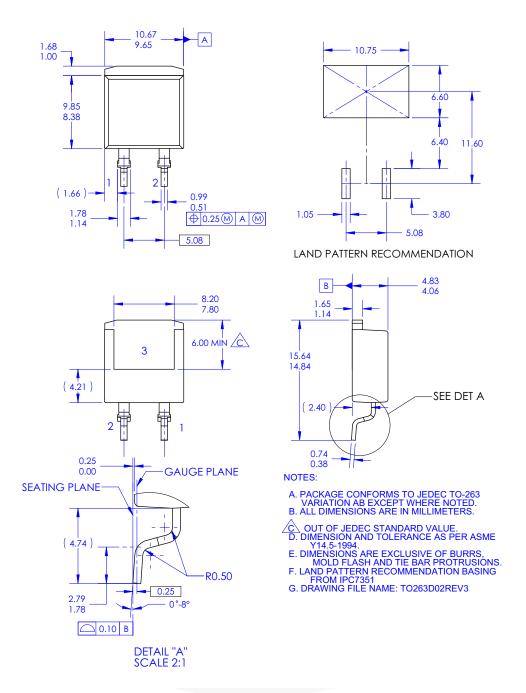


Figure 34. 2 LEAD, TO-263, JEDEC TO263 VARIATION AB, D2PAK





TRADEMARKS

The following includes registered and unregistered trademarks and service marks, owned by Fairchild Semiconductor and/or its global subsidiaries, and is not intended to be an exhaustive list of all such trademarks.

 $\begin{array}{lll} \mathsf{AccuPower^{\mathsf{TM}}} & \mathsf{F-PFS^{\mathsf{TM}}} \\ \mathsf{AttitudeEngine^{\mathsf{TM}}} & \mathsf{FRFET}^{\mathsf{S}} \end{array}$

Awinda® Global Power Resource SM AX-CAP®* GreenBridge™

 BitSiC™
 Green FPS™

 Build it Now™
 Green FPS™ e-Series™

Current Transfer Logic™ Making Small Speakers Sound Louder

DEUXPEED® and Better™

Dual Cool™ MegaBuck™

EcoSPARK® MICROCOUPLER™

EfficientMax™ MicroFET™

ECOSPARK MICROCOU
EfficientMax™ MicroFET™
ESBC™ MicroPak™
MicroPak™
MicroPak™

Fairchild® MillerDrive™
Fairchild Semiconductor®
FACT Quiet Series™ MTI®
FAST®
FAST®
FASTV
FastvCore™ MVN®
FETBench™ MWSaver®

OptoHiT™ OPTOLOGIC[®] OPTOPLANAR®

PowerTrench® PowerXS™

Programmable Active Droop™

QFET[®]
QS™
Quiet Series™
RapidConfigure™

Saving our world, 1mW/W/kW at a time™

SignalWise™ SmartMax™ SMART START™

Solutions for Your Success™

Solutions for You SPM® STEALTH™ SuperFET® SuperSOT™-3 SuperSOT™-6 SuperSOT™-8 SupreMOS® SyncFET™ Sync-Lock™ SYSTEM STERNER ST.

TinyBoost®
TinyBuck®
TinyCalc™
TinyLogic®
TINYOPTO™
TinyPower™
TinyPWM™
TinyWire™
TranSiC™
TriFault Detect™

TriFault Detect™
TRUECURRENT®*
uSerDes™

SerDes UHC®

Ultra FRFET™
UniFET™
VCX™
VisualMax™
VoltagePlus™
XS™
Xsens™
仙童™

DISCLAIMER

FPSTM

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. TO OBTAIN THE LATEST, MOST UP-TO-DATE DATASHEET AND PRODUCT INFORMATION, VISIT OUR WEBSITE AT http://www.fairchildsemi.com. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE PRODUCTS.

LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

As used herein:

- 1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.
- A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

ANTI-COUNTERFEITING POLICY

Fairchild Semiconductor Corporation's Anti-Counterfeiting Policy. Fairchild's Anti-Counterfeiting Policy is also stated on our external website, www.fairchildsemi.com, under Sales Support.

Counterfeiting of semiconductor parts is a growing problem in the industry. All manufacturers of semiconductor products are experiencing counterfeiting of their parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, failed applications, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Fairchild strongly encourages customers to purchase Fairchild parts either directly from Fairchild or from Authorized Fairchild Distributors who are listed by country on our web page cited above. Products customers buy either from Fairchild directly or from Authorized Fairchild Distributors are genuine parts, have full traceability, meet Fairchild's quality standards for handling and storage and provide access to Fairchild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address any warranty issues that may arise. Fairchild will not provide any warranty coverage or other assistance for parts bought from Unauthorized Sources. Fairchild is committed to combat this global problem and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

PRODUCT STATUS DEFINITIONS

Definition of Terms

Definition of Terms			
Datasheet Identification		Definition	
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.	
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.	
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.	
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.	

Rev. 173

^{*} Trademarks of System General Corporation, used under license by Fairchild Semiconductor.